Paweł Piotr Michałowski was born in Poznań, Poland in 1984. He obtained his Master's degree in physics from Umeå University (Sweden) in 2007 and Adam Mickiewicz University (Poznań, Poland) in 2008. In 2015 he obtained a Ph.D. degree in physics from Adam Mickiewicz University (Poznań, Poland). His scientific interest focuses on the secondary ion mass spectrometry (SIMS) technique since 2007 when he worked at Fraunhofer Center for Nanoelectronics Technologies (Dresden, Germany). Since 2015 he works at Łukasiewicz Research Network – Institute of Microelectronics and Photonics (previously known as Institute of Electronic Materials Technology) and is responsible for CAMECA IMS SC Ultra spectrometer. At the beginning of 2020, he became the Head of the Department of Structural Research and Materials Characterization which was later renamed to Characterization of Materials and Devices Research Group. He is cooperating with more than fifty institutions, both, academia and industry. He is currently focusing on developing dedicated measurement procedures - tailored for specific samples – that allow reaching a subnanometer depth resolution and enable characterization of 2D materials like graphene, hexagonal boron nitride, transition metal dichalcogenides, and MXenes. These procedures can also be applied to the analysis of full structures of semiconductor devices like VCSEL, solar cells, or various transistors.